## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10622294	CHOWN, DAVID
Examiner	Art Unit
Liu, Li	2613

SEARCHED				
Class	Subclass	Date	Examiner	
372	102	08/03/2006	LL	
398	41-43, 152, 129, 58, 122, 125	08/03/2006, 02/08/2007	LL	
385	12, 24, 93, 49	08/03/2006, 02/08/2007	LL	
250	25	08/03/2006	LL	

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST			
USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	08/03/2006, 02/08/2007	LL •	
Google	. 08/03/2006	LL ·	
IEEE	08/03/2006	LL	

INTERFERENCE SEARCH				
Subclass	Date	Examine		